Customized PTO/SB/08a+b (07-05)

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Substitute for Form 1449APTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application #	10/569,963
	Confirmation #	3348
	Filing Date	February 28, 2006
	First Inventor	CUBRIC
	Art Unit	
	Examiner	
Sheet 1 of 1	Docket #	P08870US00/MP

		U.S. PATE	ENT DOCUMENTS	
Exam.	Document No.	Publ. Date	Name	Relevance
Initial*	Number - Kind	MM-DD-YYYY	Patentee or Applicant	Passages/Figs
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NON PATENT LITERATURE DOCUMENTS			
Exam. Initial*	Include NAME of the author (in CAPS), Title of Article/Item, Date, Page(s), Volume-Issue No., Publisher, City and/or Country where published	Trans- lation	
	H.W. MOOK and P. KRUIT, Construction and characterization of the fringe field monochromator for a field emission gun, Ultramicroscopy 81 (2000) 129-139		

Examiner Signature	/Hanway Chang/	Date Considered	05/21/2009

^{*} Examiner: Initial if considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.